

<b>Notice of References Cited</b>	Application/Control No. 10/798,577	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,882,595	11-1989	Trueba et al.	347/85
	C	US-5,308,442	05-1994	Taub et al.	216/27
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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